

<b>NOTICE OF REVISION (NOR)</b>  This revision described below has been authorized for the document listed.			1. DATE (YYMMDD)  95-06-16	Form Approved OMB No. 0704-0188						
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4. ORIGINATOR  a. TYPED NAME (First, Middle Initial, Last)	b. ADDRESS (Street, City, State, Zip Code)  Defense Electronic Supply Center 1507 Wilmington Pike Dayton, OH 45444-5270		5. CAGE CODE 67268  7. CAGE CODE 67268	6. NOR NO. 5962-R157-95  8. DOCUMENT NO. <b>5962-88542</b>						
9. TITLE OF DOCUMENT MICROCIRCUIT, LINEAR, 12-BIT A/D CONVERTER, HYBRID		10. REVISION LETTER <table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <td style="width: 50%; text-align: center;">a. CURRENT A</td> <td style="width: 50%; text-align: center;">b. NEW B</td> </tr> </table>		a. CURRENT A	b. NEW B	11. ECP NO. N/A				
a. CURRENT A	b. NEW B									
12. CONFIGURATION ITEM (OR SYSTEM) TO WHICH ECP APPLIES ALL										
13. DESCRIPTION OF REVISION  Sheet 1: Revisions ltr column; add "B". Revisions description column; add "Changes in accordance with NOR 5962-R157-95 Revisions date column; add "95-06-16". Revision level block; add "B". Rev status of sheets; For sheets 1, 5, and 6 add "B".  Sheet 5: Table I; delete the following tests: Aperture jitter ( $t_{AJ}$ ), Aperture delay ( $t_{AD}$ ), and Track/Hold acquisition ( $t_{A(T/H)}$ ).  Sheet 6: Table I; For the test $V_{OL}$ change in the condition block $I_{OL} = 4.8 \text{ mA}$ to $I_{OL} = 3.2 \text{ mA}$ .  Sheet 6: Table I; For the $V_{OL}$ test change the max limit from 0.4 to 0.5.										
14. THIS SECTION FOR GOVERNMENT USE ONLY										
a. (X one)		<table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <td style="width: 10%; text-align: center;">X</td> <td>(1) Existing document supplemented by the NOR may be used in manufacture.</td> </tr> <tr> <td style="text-align: center;"></td> <td>(2) Revised document must be received before manufacturer may incorporate this change.</td> </tr> <tr> <td style="text-align: center;"></td> <td>(3) Custodian of master document shall make above revision and furnish revised document.</td> </tr> </table>			X	(1) Existing document supplemented by the NOR may be used in manufacture.		(2) Revised document must be received before manufacturer may incorporate this change.		(3) Custodian of master document shall make above revision and furnish revised document.
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b. ACTIVITY AUTHORIZED TO APPROVE CHANGE FOR GOVERNMENT			c. TYPED NAME (First, Middle Initial, Last)							
d. TITLE Branch Chief, Electronic Components Branch		e. SIGNATURE Kendall A. Cottongim		f. DATE SIGNED (YYMMDD) 95-06-16						
15a. ACTIVITY ACCOMPLISHING REVISION DESC-ELDT		b. REVISION COMPLETED (Signature) Steve L. Duncan		c. DATE SIGNED (YYMMDD) 95-06-16						

REVISIONS																			
LTR	DESCRIPTION										DATE (YR-MO-DA)				APPROVED				
A	Add end-point limit to table I snr test. Update document to current requirements of MIL-H-38534. Editorial changes throughout.										93-01-25				K. A. Cottongim				
<p>THE ORIGINAL FIRST PAGE OF THIS DRAWING HAS BEEN REPLACED.</p>																			
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REV STATUS OF SHEETS				REV		A	A	A	A	A	A	A	A	A	A	A	A		
				SHEET		1	2	3	4	5	6	7	8	9	10	11	12	13	
PMIC N/A				PREPARED BY Robert M. Heber						DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444									
<b>STANDARDIZED MILITARY DRAWING</b>  THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE  AMSC N/A				CHECKED BY Donald R. Osborne															
				APPROVED BY Williams K. Heckman															
				DRAWING APPROVAL DATE 90-05-31															
				REVISION LEVEL A						SIZE <b>A</b>	CAGE CODE <b>67268</b>		<b>5962-88542</b>						
						SHEET		1		OF		13							

# 1. SCOPE

1.1 Scope. This drawing describes device requirements for class H hybrid microcircuits to be processed in accordance with MIL-H-38534.

1.2 Part or Identifying Number (PIN). The complete PIN shall be as shown in the following example:

<u>5962-88542</u>	<u>01</u>	<u>X</u>	<u>X</u>
Drawing number	Device type (see 1.2.1)	Case outline (see 1.2.2)	Lead finish (see 1.2.3)

1.2.1 Device type(s). The device type(s) shall identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	ADC00300	12-bit track/hold A/D converter

1.2.2 Case outline(s). The case outline(s) shall be as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
X	See figure 1	40	Dual-in-line
Y	See figure 1	40	Flat pack

1.2.3 Lead finish. The lead finish shall be as specified in MIL-H-38534. Finish letter "X" shall not be marked on the microcircuit or its packaging. The "X" designation is for use in specifications when lead finishes A, B, and C are considered acceptable and interchangeable without preference.

1.3 Absolute maximum ratings.

Positive supply voltage range ( $V_{CC}$ )	...	-0.3 V dc to +18 V dc
Negative supply voltage range ( $V_{EE}$ )	...	+0.3 V dc to -18 V dc
Logic supply voltage range ( $V_{DD}$ )	...	-0.3 V dc to +7.0 V dc
Analog input voltage	...	$\pm 20$ V dc
Logic input voltage range	...	-0.3 V dc to $V_{DD}$
Power dissipation ( $T_C = +125^\circ\text{C}$ )	...	4.5 W
Storage temperature range	...	$-65^\circ\text{C}$ to $+150^\circ\text{C}$
Lead temperature (soldering, 10 seconds)	...	$+300^\circ\text{C}$
Junction temperature ( $T_J$ )	...	$+150^\circ\text{C}$
Thermal resistance, junction-to-case ( $\theta_{JC}$ )	...	$5.7^\circ\text{C/W}$
Thermal resistance, case-to-ambient ( $\theta_{CA}$ )	...	$15^\circ\text{C/W}$

1.4 Recommended operating conditions.

Positive supply voltage range ( $V_{CC}$ )	...	+14.25 V dc to +15.75 V dc
Negative supply voltage range ( $V_{EE}$ )	...	-14.25 V dc to -15.75 V dc
Logic supply voltage range ( $V_{DD}$ )	...	+4.75 V dc to +5.25 V dc
Logic input voltage range	...	0 V dc to +5.0 V dc
Analog input voltage	...	$\pm 10$ V dc
Case operating temperature range ( $T_C$ )	...	$-55^\circ\text{C}$ to $+125^\circ\text{C}$

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## 2. APPLICABLE DOCUMENTS

2.1 Government specification and standards. Unless otherwise specified, the following specification and standards of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

### SPECIFICATION

#### MILITARY

MIL-H-38534 - Hybrid Microcircuits, General Specification for.

### STANDARDS

#### MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

MIL-STD-1835 - Microcircuit Case Outlines.

(Copies of the specification and standards required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

## 3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with MIL-H-38534 and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-H-38534 and herein.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.2 and figure 1 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 2.

3.2.3 Block diagram(s). The block diagram(s) shall be as specified on figure 3.

3.2.4 Timing diagram(s). The timing diagram(s) shall be as specified on figure 4.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-H-38534. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in QML-38534 (see 6.6 herein).

3.6 Manufacturer eligibility. In addition to the general requirements of MIL-H-38534, the manufacturer of the part described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, produced on the certified line, for each device type listed herein. The data should also include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DESC-EC) upon request.

3.7 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in QML-38534 (see 6.6 herein). The certificate of compliance submitted to DESC-EC prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-H-38534 and the requirements herein.

3.8 Certificate of conformance. A certificate of conformance as required in MIL-H-38534 shall be provided with each lot of microcircuits delivered to this drawing.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions $\frac{1}{-55^{\circ}\text{C} \leq T_C \leq +125^{\circ}\text{C}}$ unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Positive supply current	$I_{CC}$	$+14.25\text{ V} \leq V_{CC} \leq +15.75\text{ V}$	1,2,3	01		+100	mA
Negative supply current	$I_{EE}$	$-14.25\text{ V} \leq V_{EE} \leq -15.75\text{ V}$	1,2,3	01	-120		mA
Logic supply current	$I_{DD}$	$+4.5\text{ V} \leq V_{DD} \leq +5.5\text{ V}$	1,2,3	01		+250	mA
Linearity error	LE	Best straight line of readings at +FS, +1/2 FS, 0, -1/2 FS, and -FS, [(Max deviation)/(V range in)] x 100	4	01	-0.025	+0.025	%FSR
			5		-0.045	+0.045	
			6		-0.041	+0.041	
Gain error	AE	$[(V_{+FS} - V_{-FS})/(V \text{ range in}) - 1] \times 100$	4	01	-0.3	+0.3	%FSR
			5		-0.6	+0.6	
			6		-0.52	+0.52	
Offset error	OE	$[(V \text{ for zero code reading}) / (V \text{ range in})] \times 100$	4	01	-0.5	+0.5	%FSR
			5		-0.7	+0.7	
			6		-0.66	+0.66	
Differential linearity error	DLE	6 $V_{p-p} \pm 5\%$ , 100 kHz $\pm 10\%$ sine wave to 5 V range in > 400 k point histogram corrected for the sine wave probability density function	4	01	-1	+1	LSB
			5,6		-3	+3	
Conversion rate	$f_C$	Encode command rate 2 MHz	4,5,6	01	0	2	MHz
In-band harmonics	IBH	rms signal - rms harmonic, $V_{IN} = 4.8\text{ V}_{p-p} \pm 2\%$ at 97656 Hz $\pm 1000\text{ ppm}$	4	01	68		dB below FSR
			5,6		66		

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <sup>1/</sup> -55°C ≤ T <sub>C</sub> ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Signal to noise ratio	SNR	rms signal - rms noise	4,5,6	01	65		dB
		End-point, T <sub>C</sub> = +25°C, rms signal - rms noise	4	01	63.5		
Input bandwidth, large signal	LSBW	V <sub>IN</sub> = 1 dB below full <sup>2/</sup> scale	4,5,6	01	10		MHz
Aperture jitter	t <sub>AJ</sub>	Uncertainty of 100 <sup>2/</sup> readings of aperture delay	9,10,11	01		16	ps rms
Aperture delay	t <sub>AD</sub>	±2.5 V/μs ramp input <sup>2/</sup> to 5 V range in, encode command at zero crossing	9,10,11	01		100	ns
Overvoltage recovery	t <sub>OVR</sub>	V <sub>IN</sub> = input step of <sup>2/</sup> twice full scale	9,10,11	01		5	μs
Trach/hold acquisition	t <sub>A(T/H)</sub>	FS change <sup>2/</sup>	9,10,11	01		100	ns
Positive output reference voltage	+V <sub>REF</sub>	+I <sub>REF</sub> = +2 mA	4	01	+9.935	+10.065	V
			5		+9.895	+10.105	
			6		+9.919	+10.081	
Negative output reference voltage	-V <sub>REF</sub>	-I <sub>REF</sub> = -2 mA	4	01	-9.950	-10.050	V
			5		-9.930	-10.070	
			6		-9.934	-10.066	
Encode command input pulse width	t <sub>PW</sub>	<sup>2/</sup>	9,10,11	01	50	<sup>3/</sup>	ns
Encode command input current	I <sub>IN(EC)</sub>	V <sub>IN</sub> = V <sub>DD</sub> or GND	1,2,3	01	-100	+100	μA
Output data invert input loading current	I <sub>LOD</sub>	V <sub>IN</sub> = V <sub>DD</sub> or GND	1,2,3	01	-150	+150	μA

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <sup>1/</sup> -55°C ≤ T <sub>C</sub> ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Enable data input loading current	I <sub>LED</sub>	V <sub>IN</sub> = V <sub>DD</sub> or GND	1,2,3	01	-100	+100	μA
Logic "0" output voltage (data ready and MUX enable outputs)	V <sub>OL</sub>	I <sub>OL</sub> = 4.8 mA	1,2,3	01		0.4	V
Logic "1" output voltage (data ready, and MUX enable outputs)	V <sub>OH</sub>	I <sub>OH</sub> = -80 μA	1,2,3	01	3.7		V
Output high-impedance current (parallel data)	I <sub>OZH</sub>	V <sub>OZH</sub> = 2.4 V	1,2,3	01		+50	μA
	I <sub>OZL</sub>	V <sub>OZL</sub> = 0.7 V	1,2,3	01		-50	μA

1/ All tests of table I shall be performed with t<sub>PW</sub> set at 50 ns minimum, t<sub>r</sub> and t<sub>f</sub> at 10 to 90 percent set to 25 ns minimum, and an encode command rate of 2 MHz maximum.

2/ Parameter shall be tested as part of device initial characterization and after design and process changes. Parameter shall be guaranteed to the limits specified in table 1 for all lots not specifically tested.

3/ Maximum encode command pulse width = (1/f<sub>C</sub>) - 50.

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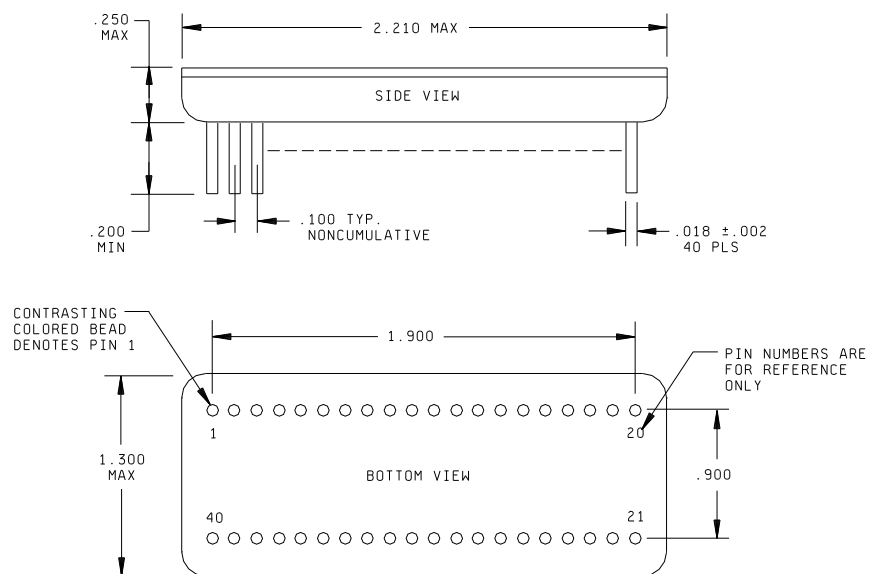
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# Case outline X



Inches	mm
.002	0.05
.018	0.46
.100	2.54
.200	5.08
.250	6.35
.900	22.86
1.300	33.02
1.900	48.26
2.210	56.13

## NOTES:

1. Dimensions are in inches.
2. Metric equivalents are given for general information only.
3. Unless otherwise specified, tolerance is ±.005 (0.13 mm).

FIGURE 1. Case outlines.

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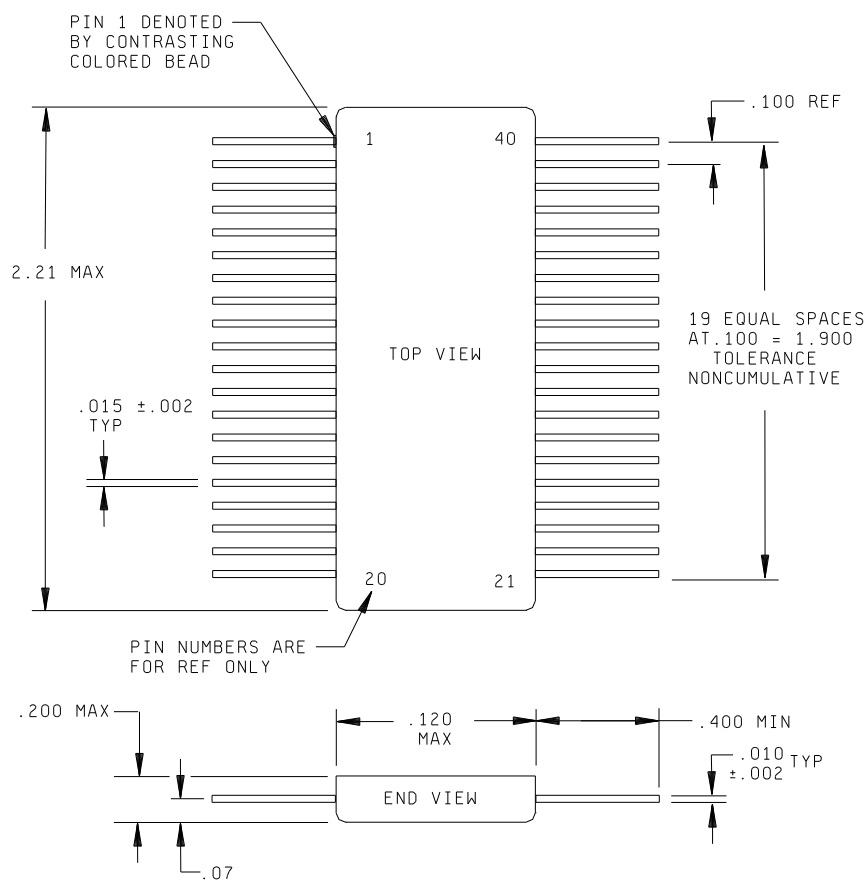
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# Case outline Y



Inches	mm
.002	0.05
.010	0.25
.015	0.38
.07	1.78
.100	2.54
.120	3.05
.200	5.08
.400	10.16
1.900	48.26
2.21	56.10

## NOTES:

1. Dimensions are in inches.
2. Metric equivalents are given for general information only.
3. Unless otherwise specified, tolerance is ±.005 (0.13 mm).

FIGURE 1. Case outlines - Continued.

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Device types	All	Device types	All
Case outlines	X and Y	Case outlines	X and Y
Terminal number	Terminal symbol	Terminal number	Terminal symbol
1	Bit 8	21	5 V range in
2	Bit 7	22	10 V range in
3	Bit 6	23	20 V range in
4	Bit 5	24	Offset adjust
5	Bit 4	25	Range offset
6	Bit 3	26	+10 V ref. out
7	Bit 2	27	-10 V ref. out
8	Bit 1 (MSB)	28	(V <sub>EE</sub> )
9	Data ready	29	(V <sub>CC</sub> )
10	+5 V input	30	NC (factory test point)
11	NC (factory test point)	31	MUX enable
12	(V <sub>DD</sub> )	32	NC (factory test point)
13	Digital ground	33	NC (factory test point)
14	Gain adjust	34	Output data invert
15	Analog ground	35	Bit 1 (MSB)
16	Analog ground	36	Enable data
17	Analog ground	37	Bit 12 (LSB)
18	Encode command	38	Bit 11
19	NC (factory test point)	39	Bit 10
20	NC (factory test point)	40	Bit 9

FIGURE 2. Terminal connections.

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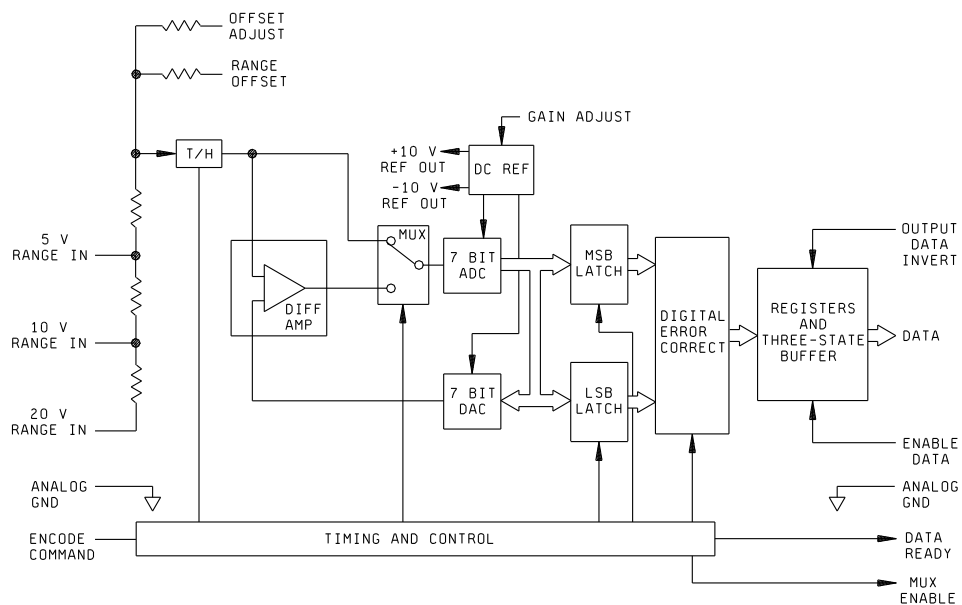


FIGURE 3. Block diagrams.

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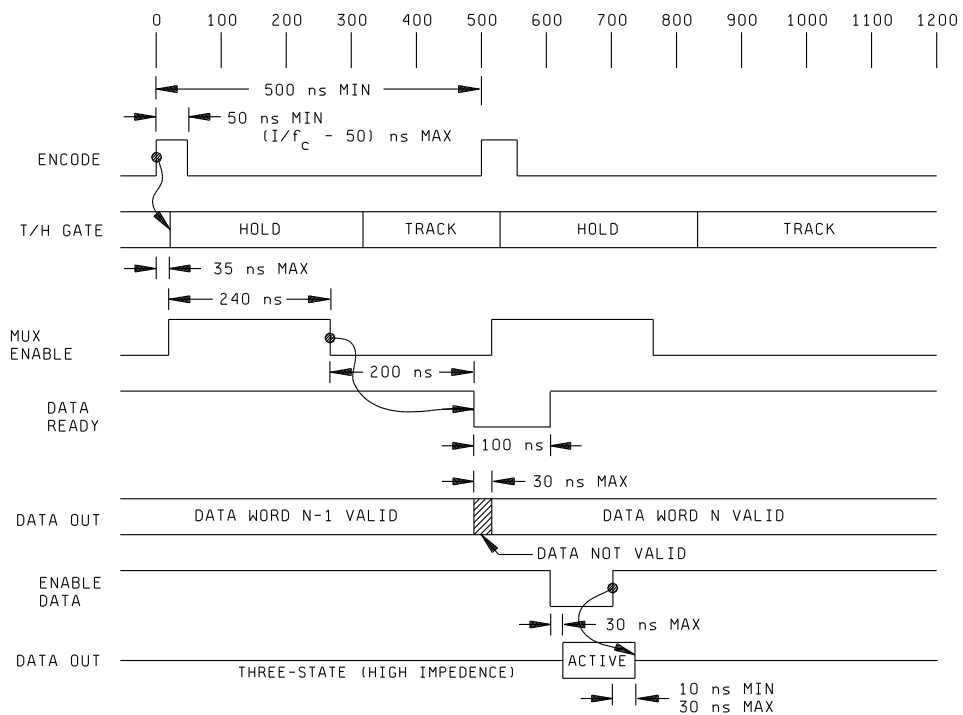


FIGURE 4. Timing diagrams.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (in accordance with method 5008, group A test table)
Interim electrical parameters	1
Final electrical test parameters	1*,2,3,4,5,6,9
Group A test requirements	1,2,3,4,5,6,9,10,11
Group C end-point electrical parameters	1,2,3,4

\* PDA applies to subgroup 1.

#### 4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-H-38534.

4.2 Screening. Screening shall be in accordance with MIL-H-38534. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DESC-EC or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.

(2)  $T_C$  as specified in accordance with table I of method 1015 of MIL-STD-883.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with MIL-H-38534 and as specified herein.

4.3.1 Group A inspection. Group A inspection shall be in accordance with MIL-H-38534 and as follows:

a. Tests shall be as specified in table II herein.

b. Subgroups 7 and 8 shall be omitted.

4.3.2 Group B inspection. Group B inspection shall be in accordance with MIL-H-38534.

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4.3.3 Group C inspection. Group C inspection shall be in accordance with MIL-H-38534 and as follows:

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test, method 1005 of MIL-STD-883.
  - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DESC-EC or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
  - (2)  $T_C$  as specified in accordance with table I of method 1005 of MIL-STD-883.
  - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.3.4 Group D inspection. Group D inspection shall be in accordance with MIL-H-38534.

## 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-H-38534.

## 6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

6.4 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-EC, telephone (513) 296-6047.

6.5 Comments. Comments on this drawing should be directed to DESC-EC, Dayton, Ohio 45444, or telephone (513) 296-5373.

6.6 Approved sources of supply. Approved sources of supply are listed in QML-38534. Additional sources will be added to QML-38534 as they become available. The vendors listed in QML-38534 have agreed to this drawing and a certificate of compliance (see 3.7 herein) has been submitted to and accepted by DESC-EC.

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## STANDARDIZED MILITARY DRAWING SOURCE APPROVAL BULLETIN

DATE: 93-01-25

Approved sources of supply for SMD 5962-88542 are listed below for immediate acquisition only and shall be added to QML-38534 during the next revision. QML-38534 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DESC-EC. This bulletin is superseded by the next dated revision of QML-38534.

Standardized military drawing PIN	Vendor CAGE number	Vendor similar PIN <u>1/</u>
5962-8854201XX	19645	ADC00300-112
5962-8854201YX	19645	ADC00302-112

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE  
number

19645

Vendor name  
and address

ILC Data Device Corporation  
105 Wilbur Place  
Bohemia, NY 11716

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in this information bulletin.